

Search Notes

Application/Control No.

10/647,163

Examiner

Hanh Nguyen

Applicant(s)/Patent under
Reexamination

LOU ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	203	6/7/2007	HN
	210		
	208		
	342		
	320		
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	441		
	274		
	202		
	212		
370	215		
375	241		
	262		
375	240.28		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	6/7/2007	HN